

**N-Ch and P-Channel MOSFET** 

#### **General Description**

The WSP4606 is the highest performance trench N-ch and P-ch MOSFETs with extreme high cell density , which provide excellent RDSON and gate charge for most of the synchronous buck converter applications .

The WSP4606 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

#### Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

### **Product Summery**

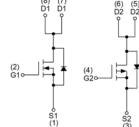
BVDSS	RDSON	ID
30V	18mΩ	7A
-30V	30mΩ	-6A

#### Applications

- Power management in half bridge and inverters
- DC-DC Converter
- Load Switch

#### **SOP-8 Pin Configuration**





## **Absolute Maximum Ratings**

Symbol	Parameter	Rat		
Symbol	Falameter	N-Channel	P-Channel	Units
V <sub>DS</sub>	Drain-Source Voltage	30	-30	V
V <sub>GS</sub>	Gate-Source Voltage	±20	±20	V
I <sub>D</sub> @T <sub>C</sub> =25℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	7.0	-6	А
I <sub>D</sub> @T <sub>C</sub> =100℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	6	-4	А
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	20	-12	А
EAS	Single Pulse Avalanche Energy <sup>3</sup>	72	59	mJ
I <sub>AS</sub>	Avalanche Current	21	-19	А
P <sub>D</sub> @T <sub>C</sub> =25℃	Total Power Dissipation <sup>4</sup>	2.5	2.08	W
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C

## **Thermal Data**

Symbol	Parameter	Тур.	Max.	Unit
R <sub>eja</sub>	Thermal Resistance Junction-Ambient <sup>1</sup>		85	°C/W
R <sub>θJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>		50	°C/W



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## Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	30			V
$\triangle BV_{DSS} / \triangle T_J$	BVDSS Temperature Coefficient	Reference to 25 $^\circ\!\mathrm{C}$ , I_D=1mA		0.034		V/℃
Parata	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =6A		18	28	mΩ
R <sub>DS(ON)</sub>		V <sub>GS</sub> =4.5V , I <sub>D</sub> =5A		25	32	1112.2
V <sub>GS(th)</sub>	Gate Threshold Voltage		1.0	1.5	2.5	V
$ riangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS} = V_{DS}$ , $I_D = 2500A$		-5.8		mV/℃
		V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , T <sub>J</sub> =25℃			1	uA uA
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , T <sub>J</sub> =55℃			5	
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}=\pm20V$ , $V_{DS}=0V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =15V , I <sub>D</sub> =5A		10		S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , f=1MHz		2.5		Ω
Qg	Total Gate Charge (4.5V)			7.2		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> =20V , V <sub>GS</sub> =4.5V , I <sub>D</sub> =6A		1.4		nC
Q <sub>gd</sub>	Gate-Drain Charge			2.2		
T <sub>d(on)</sub>	Turn-On Delay Time			4.1		
Tr	Rise Time	$V_{DD}$ =12V , $V_{GS}$ =10V , $R_{G}$ =3.3 $\Omega$		9.8		
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =5A		15.5		ns
T <sub>f</sub>	Fall Time			6.0		1
C <sub>iss</sub>	Input Capacitance			550		
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =25V , V <sub>GS</sub> =0V , f=1MHz		68		pF
Crss	Reverse Transfer Capacitance			55		

### **Guaranteed Avalanche Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy $^5$	V <sub>DD</sub> =25V , L=0.1mH , I <sub>AS</sub> =10A	16			mJ

#### **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current <sup>1,6</sup>	$V_G = V_D = 0V$ , Force Current			7	А
I <sub>SM</sub>	Pulsed Source Current <sup>2,6</sup>				20	A
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =5A , T <sub>J</sub> =25℃			1.2	V

Note :

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper,t<10sec.

2.The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%

3. The EAS data shows Max. rating . The test condition is  $V_{DD}$ =25V,  $V_{GS}$ =10V, L=0.1mH,  $I_{AS}$ =10A

4.The power dissipation is limited by 150  $^\circ\!\!\mathbb{C}$   $\,$  junction temperature

5.The Min. value is 100% EAS tested guarantee.

6.The data is theoretically the same as  $I_{\text{D}}$  and  $I_{\text{DM}}$  , in real applications , should be limited by total power dissipation.



**N-Ch and P-Channel MOSFET** 

## Electrical Characteristics (TJ=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-30			V
$\triangle BV_{DSS} / \triangle T_J$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25 $^\circ\!\!{\rm C}$ , I_D=-1mA		-0.085		V/℃
P	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-10V , I <sub>D</sub> =-6A		30	38	mΩ
R <sub>DS(ON)</sub>		V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-3A		48	58	1115.2
V <sub>GS(th)</sub>	Gate Threshold Voltage		-1.0	-1.5	-2.5	V
$ riangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient			0.375		mV/℃
	Drain Source Lookage Current	$V_{\text{DS}}\text{=-}24\text{V}$ , $V_{\text{GS}}\text{=}0\text{V}$ , $T_{\text{J}}\text{=}25^\circ\!\mathrm{C}$			1	uA
I <sub>DSS</sub>	Drain-Source Leakage Current	$V_{\text{DS}}\text{=-}24\text{V}$ , $V_{\text{GS}}\text{=}0\text{V}$ , $T_{\text{J}}\text{=}55^\circ\!\mathrm{C}$			5	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ = $\pm20V$ , $V_{DS}$ = $0V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>D</sub> =-6A		6		S
Qg	Total Gate Charge (-4.5V)			6.4		
Q <sub>gs</sub>	Gate-Source Charge	$V_{\text{DS}}\text{=-}20\text{V}$ , $V_{\text{GS}}\text{=-}4.5\text{V}$ , $I_{\text{D}}\text{=-}6\text{A}$		2.7		nC
Q <sub>gd</sub>	Gate-Drain Charge			3.1		
T <sub>d(on)</sub>	Turn-On Delay Time			9		
Tr	Rise Time	$V_{DD}\text{=-}12V$ , $V_{GS}\text{=-}10V$ , $R_{G}\text{=}3.3\Omega,$		16.6		ns
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =-5A		21		115
T <sub>f</sub>	Fall Time			21.6		
C <sub>iss</sub>	Input Capacitance			645		
Coss	Output Capacitance	$V_{DS}$ =-25V , $V_{GS}$ =0V , f=1MHz		272		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			105		

#### **Guaranteed Avalanche Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy $^5$	V <sub>DD</sub> =-25V , L=0.1mH , I <sub>AS</sub> =-10A	16			mJ

#### **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current <sup>1,6</sup>	$V_{G}=V_{D}=0V$ , Force Current			-6	А
I <sub>SM</sub>	Pulsed Source Current <sup>2,6</sup>				-12	А
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =-6A , T <sub>J</sub> =25℃			-1.2	V

Note :

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper,t<10 sec.

2.The data tested by pulsed , pulse width  $\leq\,$  300us , duty cycle  $\leq\,$  2%

3. The EAS data shows Max. rating . The test condition is  $V_{DD}$ =-25V,  $V_{GS}$ =-10V, L=0.1mH,  $I_{AS}$ =-10A

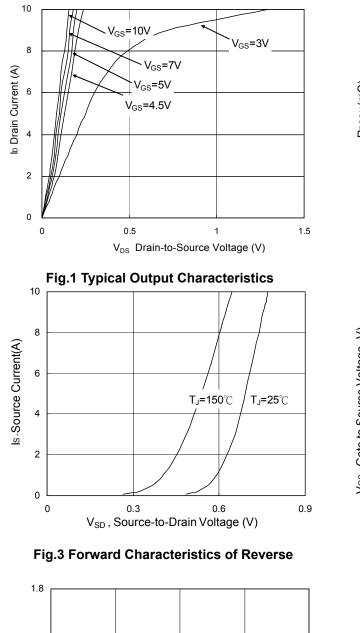
4. The power dissipation is limited by 150 °C junction temperature

5. The Min. value is 100% EAS tested guarantee.

6. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



#### N-Ch and P-Channel MOSFET



#### **N-Channel Typical Characteristics**

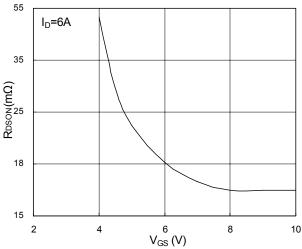


Fig.2 On-Resistance vs. G-S Voltage

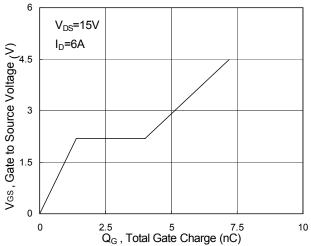
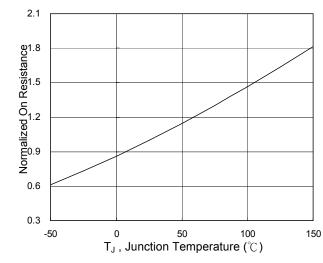
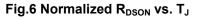


Fig.4 Gate-charge Characteristics





1.4

Normalized V<sub>GS</sub>(th) 9<sup>0</sup>

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150



#### N-Ch and P-Channel MOSFET

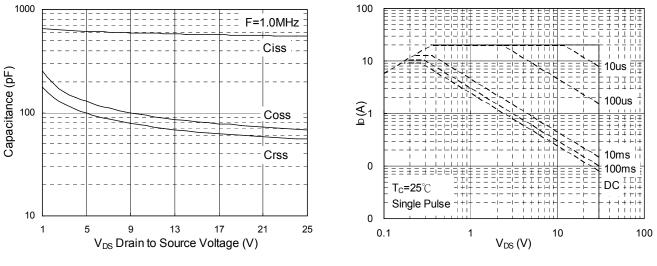


Fig.7 Capacitance

Fig.8 Safe Operating Area

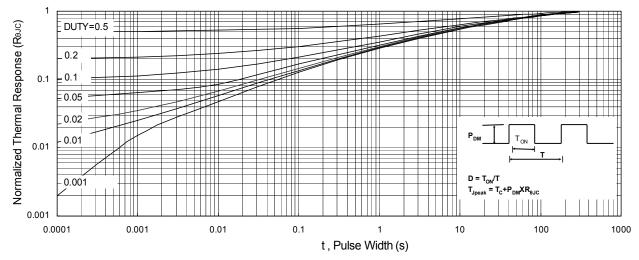
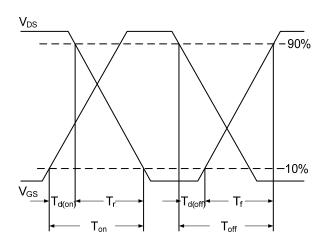
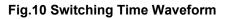
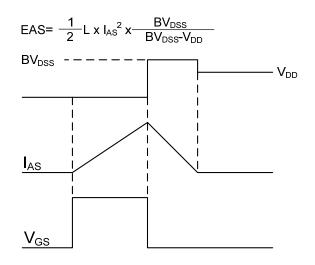


Fig.9 Normalized Maximum Transient Thermal Impedance





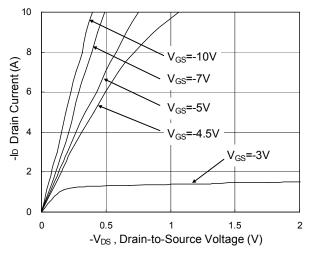






### N-Ch and P-Channel MOSFET

## **P-Channel Typical Characteristics**



**Fig.1 Typical Output Characteristics** 

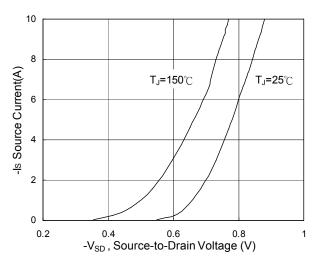
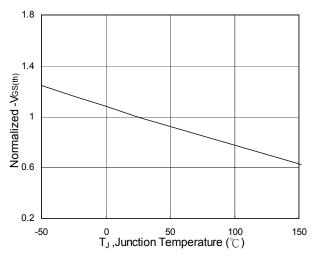
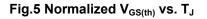


Fig.3 Forward Characteristics of Reverse





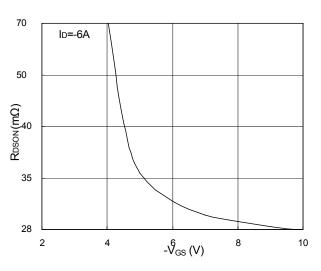
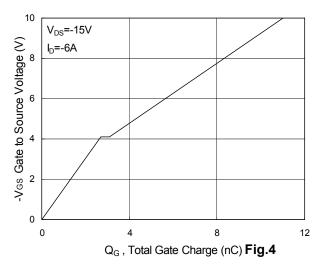
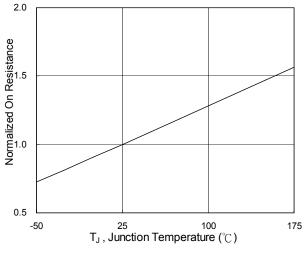


Fig.2 On-Resistance vs. Gate-Source



**Gate-charge Characteristics** 







#### N-Ch and P-Channel MOSFET

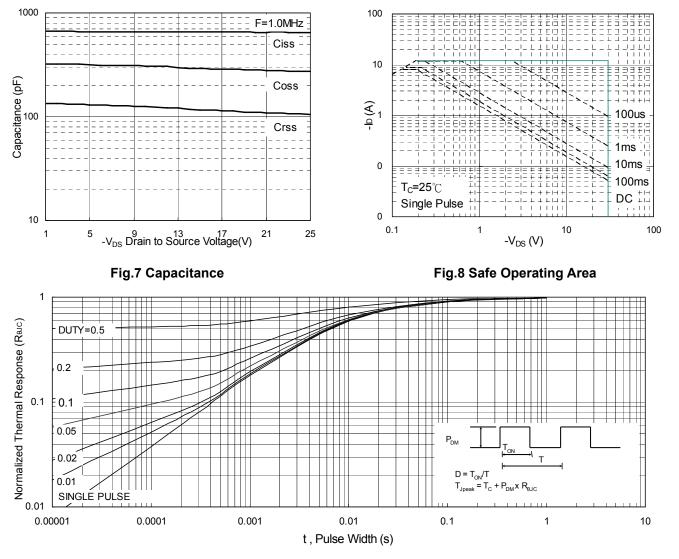
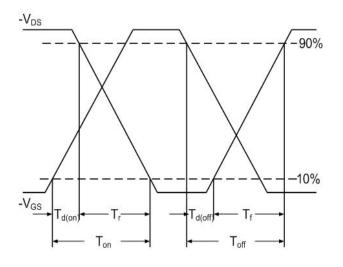
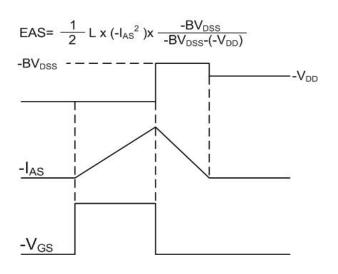


Fig.9 Normalized Maximum Transient Thermal Impedance











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